IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:	Emiko Nishida, et al.		
Docket No.:	KPO10801	Examiner	Wesley D. Markham
Filing Date:	_____	Art Unit:	1762
Title:	Apparatus for Forming an Optical Multilayer Filter		

October 14, 2003
San Francisco, California

Mail Stop Patent Application
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

Pursuant to the duty of disclosure set forth in 37 CFR § 1.56, Applicants respectfully submit the following information disclosure statement.

The undersigned certifies that each of the following references was contained in a communication from the EPO in a counterpart foreign application not more than three months prior to the filing of this statement.

The disclosed references are:

C. Grèzes-Bessset, et al., "Synthesis and research of the optimum conditions for the optical monitoring of non-quarter-wave multilayers," Applied Optics, Optical Society of America, Washington, US, vol. 32, no. 28, Oct. 1, 1993, pages 5612-5618.

S. Callard, et al., "New method for *in* situ control of Bragg reflector fabrication," Applied Physics Letters, American Institute of Physics, New York, US, vol. 68, no. 17, April 22, 1996, pages 2335-2336.

M. Kildemo, et al., "A direct robust feedback method for growth control of optical coatings by multiwavelength ellipsometry," Thin Solid Films, Elsevier-Sequoia S.A. Lausanne, CH, vol. 313-314, Feb. 13, 1998, pages 484-489.

Applicants respectfully request that the Examiner initial the cited references shown on the enclosed form PTO-1449 and that the references be made of record in the present application.

Respectfully submitted,

David N. Lathrop, Esq.
Registration No. 34,655
601 California St., Suite 1111
San Francisco, CA 94108-2805
Telephone: (415) 989-8080
Facsimile: (415) 989-0910

Enc. Cited references (3)
PTO Form 1449
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I certify that this Information Disclosure Statement and all enclosed materials are being deposited with the United States Postal Service on October 14, 2003 as "Express Mail," mailing label EV326498507US, in an envelope addressed to Mail Stop Patent Application, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450

Jean C. Reed

Form PTO-1449 — U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT

DOCKET	S.N.
KPO10801	
APPLICANT	
Emiko Nishida, et al.	
FILING DATE	GROUP
	1762

U.S. PATENT DOCUMENTS

*Exam. Initial		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

*Exam. Initial		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES	TRANSLATION NO

OTHER DOCUMENTS (*Including Author, Title, Date, Pertinent Pages, etc.*)

			Grèzes-Bessset, et al., "Synthesis and research of the optimum conditions for the optical monitoring of non-quarter-wave multilayers," Applied Optics, Optical Society of America, Wash. US, vol 32, no 28, 10/1/93, pp..5612-5618
			S. Callard, et al., "New method for in situ control of Bragg reflector fabrication," Applied Physics Letters, American Institute of Physics, New York, US, vol. 68, no. 17, April 22, 1996, pages 2335-2336
			M. Kildemo, et al., "A direct robust feedback method for growth control of optical coatings by multiwavelength ellipsometry," Thin Solid Films, Elsevier-Sequoia S.A. Lausanne, CH, vol. 313-314, Feb. 13, 1998, pages 484-489

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP; draw line through citation if not in conformance and not considered. Include copy of this form with next communication with applicant.